Search Notes

Application/Contro	ol No.	Applicant(s)/Patent und Reexamination	ler
10/825,594		LEE, YUN-BOK	
Examiner		Art Unit	
Tai Duong		2871	

SEARCHED					
Class	Subclass	Date	Examiner		
349	38	6/17/2006	TD		
	39				
	43				
	110				
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257	59				
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INTERFERENCE SEARCHED					
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SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
EAST (US PGPUB, USPAT, EPO, JPO, DERWENT, IBM TDB) see search history printout	6/17/2006	TD
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